



#### Lecture notes Low Energy Nuclear Reactions Accelerator-driven experiments at University of Szczecin, Poland

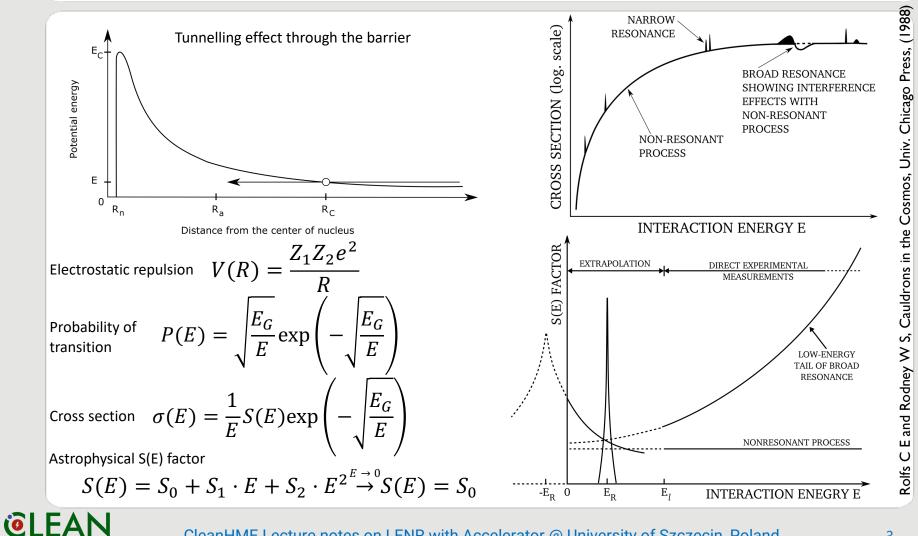
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# Motivation

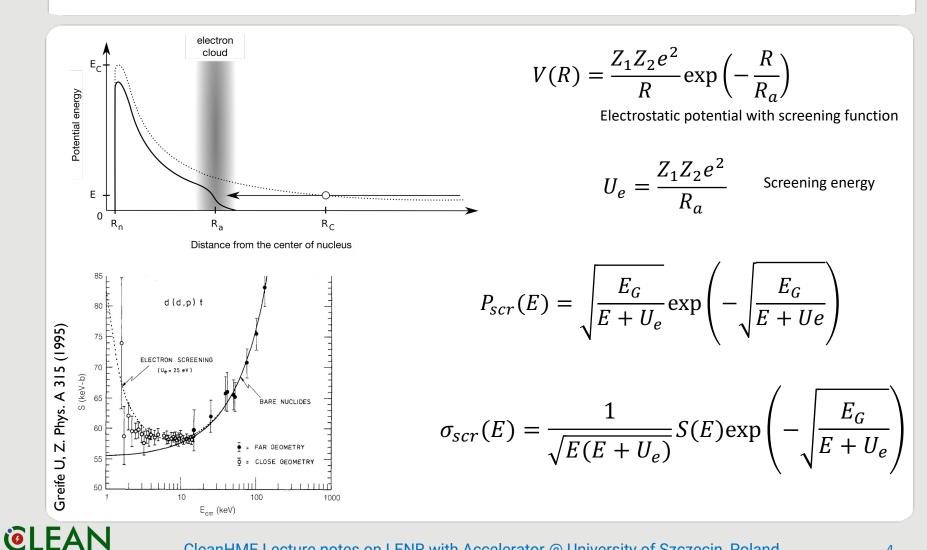
- Measurements of the screening effect in proton and deuteron induced reactions on chosen metallic alloys and nanocomposite are performed at the University of Szczecin applying an electrostatic accelerator with ultrahigh vacuum placed in *eLBRUS* laboratories.
- The system is equipped with an additional decelerating module to deliver proton and deuteron beam currents of a few mA at the cooled down or heated metallic targets at the lowest possible energies.
- This will allow for measurements of nuclear reaction cross sections at energies down to 1 keV for which reaction enhancement factor due to the screening effect reaches values larger than 1000.
- Influence of crystal lattice defects and nanostructures on the reaction rates are investigated additionally.

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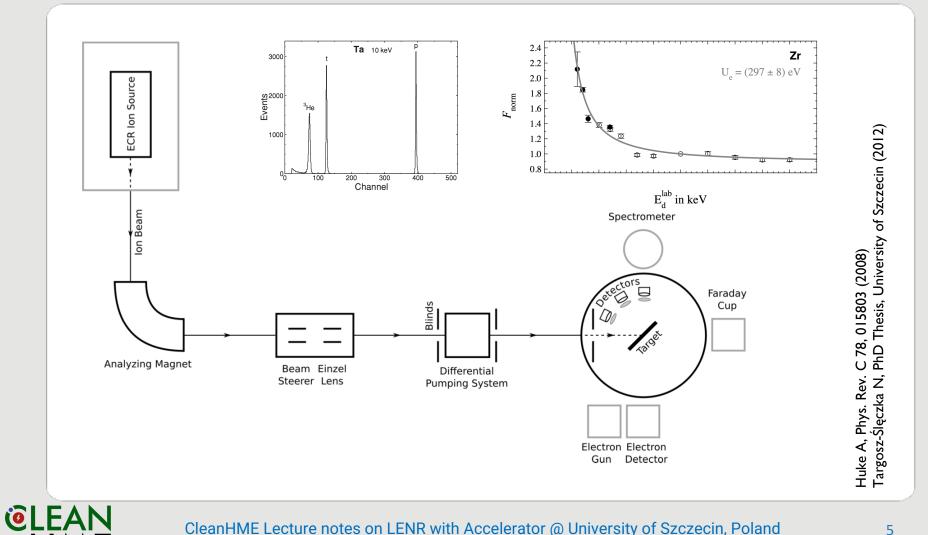
#### Nuclear reactions below Coulomb barrier



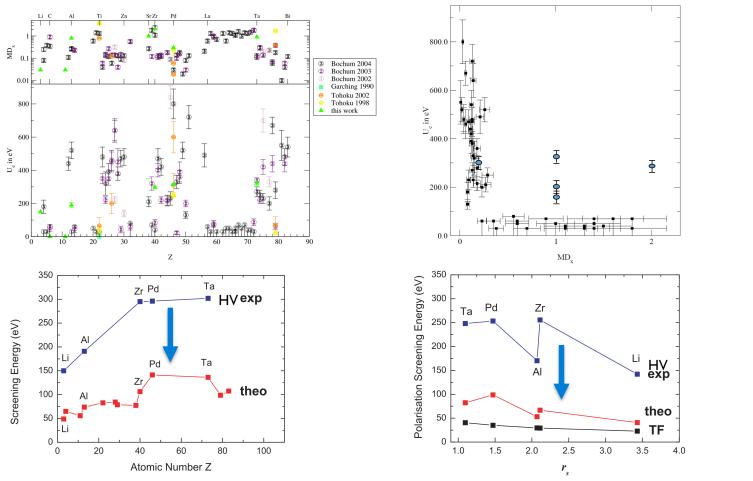
#### **Electron screening effect**



# Previous results with HV



### Extensive studies worldwide



Czerski K, Eur. Phys. J. A 27, 83 (2006) Huke A, Phys. Rev. C 78, 015803 (2008)

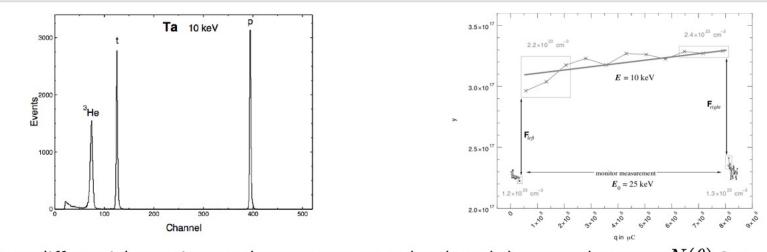


# **UHV** experimental set-up





#### Full data analysis



Three differential counting numbers were measured and total charge at the target N( heta) & q

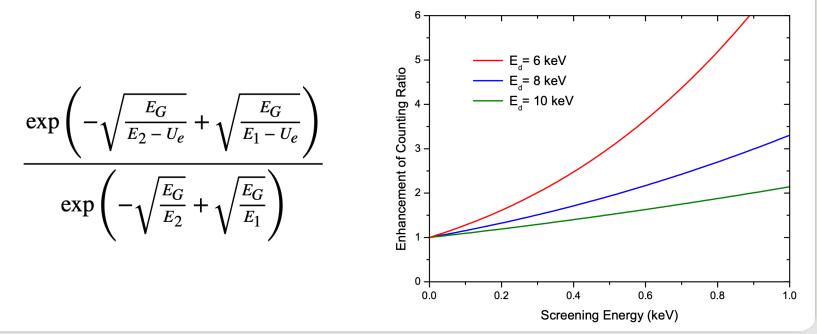
$$\begin{aligned} & \text{experimental yield} \\ & Y(E) = \frac{ze}{\varepsilon} \frac{dN}{dq} \\ & \text{thick target yield} \\ & Y_{\text{bare}}(E) = n \int_{0}^{R} \sigma_{\text{bare}}(E) dx = n \int_{0}^{E} \frac{\sigma_{\text{bare}}(E)}{\frac{dE}{dx}} dE \\ & \text{thick target enhancement factor} \\ & \text{stopping power} \\ & \frac{dE}{dx} \sim \sqrt{E} \end{aligned}$$

$$\begin{aligned} & \text{reduced yield} \\ & y(E,q) = \frac{Y_{\text{scr}}(E,q)}{\int_{0}^{E} \frac{\sigma_{\text{bare}}(E)}{\sqrt{E}} dE} \\ & \text{thick target enhancement factor} \\ & F(E) = \frac{\int_{0}^{E} \frac{\sigma_{\text{scr}}(E)}{\sqrt{E}} dE}{\int_{0}^{E} \frac{\sigma_{\text{bare}}(E)}{\sqrt{E}} dE} \end{aligned}$$

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# Estimation of electron screening

- A two-point method for estimation of the screening energy allows to evaluate whether a specific target is worth to be studied in details or not.
- It takes ratio between enhancement in counting rates at two different deuteron energies  $E_1$  (=20 keV) and  $E_2$  (low energy).







# Thank you! Any questions?

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